

Notice of References Cited	Application/Control No. 10/711,933		Applicant(s)/Patent Under Reexamination WU ET AL.	
	Examiner HENOK G. HEYI		Art Unit 2627	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,446,724 A	08-1995	Tabe et al.	369/275.1
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*	C	US-6,928,567 B2	08-2005	Nakai, Hidekazu	713/340
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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